	Application No.	Applicant(s)	en	
Notice of Allowability	Аррисанон но.	Applicant(s)	Applicant(s)	
	09/880,089	YAMAZAKI ET AL.		
Notice of Allowability	Examin r	Art Unit		
	DAVID VU	2818		
The MAILING DATE of this communication appeal claims being allowable, PROSECUTION ON THE MERITS IS derewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIFE the Office or upon petition by the applicant. See 37 CFR 1.313	(OR REMAINS) CLOSED or other appropriate comm GHTS. This application is	in this application. If not included nunication will be mailed in due co	ourse. <b>THIS</b>	
. X This communication is responsive to 09/12/03.				
<ol> <li>∴ The allowed claim(s) is/are <u>1-60</u>.</li> </ol>				
3. $\boxtimes$ The drawings filed on <u>14 June 2002</u> are accepted by the E				
<ul> <li>Acknowledgment is made of a claim for foreign priority ur</li> <li>a)</li></ul>	nder 35 U.S.C. § 119(a)-(d)	) or (f).		
<ol> <li>Certified copies of the priority documents have</li> </ol>	been received.			
<ol><li>Certified copies of the priority documents have</li></ol>	been received in Applicat	ion No		
3. Copies of the certified copies of the priority do	cuments have been receive	ed in this national stage application	n from the	
International Bureau (PCT Rule 17.2(a)).				
* Certified copies not received:				
<ol> <li>Acknowledgment is made of a claim for domestic priority u reference was included in the first sentence of the specifica-</li> </ol>	ation or in an Application D	ata Sheet. 37 CFR 1.78.	a specific	
(a) 🔲 The translation of the foreign language provisional a				
Acknowledgment is made of a claim for domestic priority u in the first sentence of the specification or in an Application	nder 35 U.S.C. §§ 120 and Data Sheet. 37 CFR 1.78	l/or 121 since a specific reference	was included	
Applicant has THREE MONTHS FROM THE "MAILING DATE" of below. Failure to timely comply will result in ABANDONMENT of	fthis communication to file this application. THIS TH	a reply complying with the require REE-MONTH PERIOD IS NOT E	ements noted XTENDABLE.	
7. A SUBSTITUTE OATH OR DECLARATION must be subm INFORMAL PATENT APPLICATION (PTO-152) which give	nitted. Note the attached Exes reason(s) why the oath	XAMINER'S AMENDMENT or NO or declaration is deficient.	TICE OF	
3. CORRECTED DRAWINGS ( as "replacement sheets") must (a) including changes required by the Notice of Draftspers		ew ( PTO-948) attached		
1) hereto or 2) to Paper No	sampation filed - 14b	ich has boon approved by the Ex	eminer	
(b) ☐ including changes required by the proposed drawing of				
(c) ☐ including changes required by the attached Examiner	s Amenament / Comment	or in the Office action of Paper No	. <u></u> .	
ldentifying indicia such as the application number (see 37 CFR 1 each sheet. Replacement sheet(s) should be labeled as such in t	.84(c)) should be written on the margin according to 37 (	the drawings in the front (not the b CFR 1.121(d).	eack) of	
9. ☐ DEPOSIT OF and/or INFORMATION about the depondant the depondent action of the second se	sit of BIOLOGICAL MA THE DEPOSIT OF BIOLOG	TERIAL must be submitted. No GICAL MATERIAL.	ote the	
Attachm nt(s)				
1☐ Notice of References Cited (PTO-892)	5☐ Notice of Ir	nformal Patent Application (PTO-1	52)	
<ul> <li>Notice of Draftperson's Patent Drawing Review (PTO-948)</li> <li>Information Disclosure Statements (PTO-1449 or PTO/SB/0 Paper No. 09/15/03</li> </ul>	6☐ Interview S	6 Interview Summary (PTO-413), Paper No		
	/ CXamilier s	: Amendment/Comment		
4 Examiner's Comment Regarding Requirement for Deposit	_	Statement of Reasons for Allowa	ance	
of Biological Material	9☐ Other			
	David Nelms			

U.S. Patent and Trademark Office PTOL-37 (Rev. 11-03) Supervisory Patent Examiner Technology Center 2800 Application/Control Number: 09/880,089

Art Unit: 2818

**DETAILED ACTION** 

Page 2

Reason for allowance

1. The following is an examiner's statement of reason for allowance: None of the references of record teaches or suggests a semiconductor device comprising thin film transistors in a pixel portion and in a driver circuit formed over a same insulating surface, semiconductor device comprising: a plurality of crystal planes as measured by EBSP method in which an electron beam of 20 nm or less in a spot diameter is irradiated to a plurality of different points of channel-forming region, wherein ratios of plurality of crystal planes which form an angle equal to or less than 10° with a substrate surface is larger or equal to 20% in [101] plane, less than or equal to 3% in [001] plane, and less than or equal to 5% in [111] plane.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance".

Conclusion

2. Any inquiry concerning this communication or earlier communications from the examiner should be directed to David Vu whose telephone number is 703-305-0391. The new

Application/Control Number: 09/880,089

Art Unit: 2818

Page 3

phone number after January 08, 2004 will be (571) 272-1798. The examiner can normally be reached on Monday-Friday 8:00am-5:30pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, David Nelms can be reached on 703-308-4910. The new phone number after January 08, 2004 will be (571) 272-1787.

The fax phone numbers for the organization where this application or proceeding is assigned is (703) 308-7722 for regular communications and for After Final communications.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is (703) 308-0956.

DV

David Vu.

Bavid Nelms
Supervisory Patent Examiner
Technology Center 2800